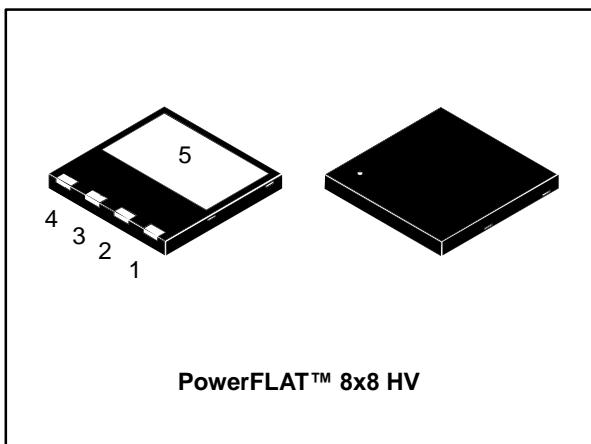
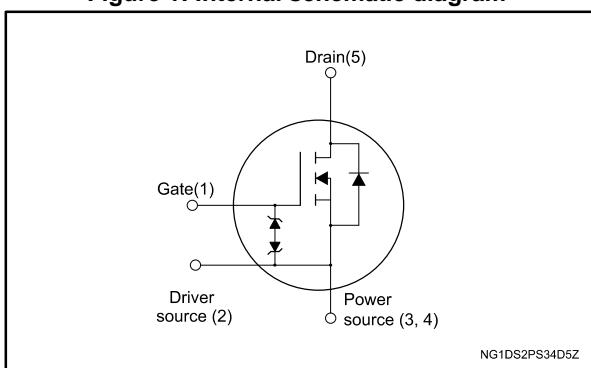


## N-channel 650 V, 0.124 Ω typ., 20 A MDmesh™ M2 Power MOSFET in a PowerFLAT™ 8x8 HV package

Datasheet - production data



**Figure 1: Internal schematic diagram**



### Features

Order code	V <sub>DS</sub>	R <sub>DS(on)max</sub>	I <sub>D</sub>
STL33N65M2	650 V	0.154 Ω	20 A

- Extremely low gate charge
- Excellent output capacitance (C<sub>oss</sub>) profile
- 100% avalanche tested
- Zener-protected

### Applications

- Switching applications

### Description

This device is an N-channel Power MOSFET developed using MDmesh™ M2 technology. Thanks to its strip layout and an improved vertical structure, the device exhibits low on-resistance and optimized switching characteristics, rendering it suitable for the most demanding high efficiency converters.

**Table 1: Device summary**

Order code	Marking	Package	Packing
STL33N65M2	33N65M2	PowerFLAT™ 8x8 HV	Tape and reel

## Contents

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# 1 Electrical ratings

**Table 2: Absolute maximum ratings**

Symbol	Parameter	Value	Unit
$V_{GS}$	Gate-source voltage	$\pm 25$	V
$I_D$	Drain current (continuous) at $T_C = 25^\circ\text{C}$	20	A
$I_D$	Drain current (continuous) at $T_C = 100^\circ\text{C}$	12.6	A
$I_{DM}^{(1)}$	Drain current (pulsed)	80	A
$P_{TOT}$	Total dissipation at $T_C = 25^\circ\text{C}$	150	W
$dv/dt^{(2)}$	Peak diode recovery voltage slope	15	V/ns
$dv/dt^{(3)}$	MOSFET $dv/dt$ ruggedness	50	V/ns
$T_{stg}$	Storage temperature range	- 55 to 150	$^\circ\text{C}$
$T_j$	Operating junction temperature range		$^\circ\text{C}$

**Notes:**

(1) Pulse width limited by safe operating area.

(2)  $I_{SD} \leq 20$  A,  $di/dt \leq 400$  A/ $\mu\text{s}$ ,  $V_{DS(\text{peak})} < V_{(\text{BR})DSS}$ ,  $V_{DD} = 400$  V.(3)  $V_{DS} \leq 520$  V.**Table 3: Thermal data**

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case max	0.83	$^\circ\text{C}/\text{W}$
$R_{thj-pcb}^{(1)}$	Thermal resistance junction-pcb max	45	$^\circ\text{C}/\text{W}$

**Notes:**(1) When mounted on FR-4 board of  $1\text{inch}^2$ , 2oz Cu.**Table 4: Avalanche characteristics**

Symbol	Parameter	Value	Unit
$I_{AR}$	Avalanche current, repetitive or not repetitive (pulse width limited by $T_{jmax}$ )	2.2	A
$E_{AS}$	Single pulse avalanche energy (starting $T_j = 25^\circ\text{C}$ , $I_D = I_{AR}$ , $V_{DD} = 50$ V)	600	mJ

## 2 Electrical characteristics

( $T_C = 25^\circ\text{C}$  unless otherwise specified)

**Table 5: On /off states**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(\text{BR})\text{DSS}}$	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}$ , $I_D = 1 \text{ mA}$	650			V
$I_{\text{DSS}}$	Zero gate voltage drain current	$V_{GS} = 0 \text{ V}$ , $V_{DS} = 650 \text{ V}$			1	$\mu\text{A}$
		$V_{GS} = 0 \text{ V}$ , $V_{DS} = 650 \text{ V}$ , $T_C = 125^\circ\text{C}$ (1)			100	$\mu\text{A}$
$I_{\text{GSS}}$	Gate-body leakage current	$V_{DS} = 0 \text{ V}$ , $V_{GS} = \pm 25 \text{ V}$			$\pm 10$	$\mu\text{A}$
$V_{GS(\text{th})}$	Gate threshold voltage	$V_{DS} = V_{GS}$ , $I_D = 250 \mu\text{A}$	2	3	4	V
$R_{DS(\text{on})}$	Static drain-source on- resistance	$V_{GS} = 10 \text{ V}$ , $I_D = 10 \text{ A}$		0.124	0.154	$\Omega$

**Notes:**

(1)Defined by design, not subject to production test.

**Table 6: Dynamic**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$C_{iss}$	Input capacitance	$V_{DS} = 100 \text{ V}$ , $f = 1 \text{ MHz}$ , $V_{GS} = 0$	-	1790	-	pF
$C_{oss}$	Output capacitance		-	75	-	pF
$C_{rss}$	Reverse transfer capacitance		-	2	-	pF
$C_{oss \text{ eq.}}^{(1)}$	Equivalent output capacitance	$V_{DS} = 0$ to $520 \text{ V}$ , $V_{GS} = 0$	-	380	-	pF
$Q_g$	Total gate charge	$V_{DD} = 520 \text{ V}$ , $I_D = 24 \text{ A}$ $V_{GS} = 10 \text{ V}$ (see <a href="#">Figure 15: "Gate charge test circuit"</a> )	-	41.5	-	nC
$Q_{gs}$	Gate-source charge		-	6.8	-	nC
$Q_{gd}$	Gate-drain charge		-	18	-	nC

**Notes:**

(1) $C_{oss \text{ eq.}}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$ .

**Table 7: Switching times**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 325 \text{ V}$ , $I_D = 12 \text{ A}$ $R_G = 4.7 \Omega$ , $V_{GS} = 10 \text{ V}$ (see <a href="#">Figure 14: "Switching times test circuit for resistive load"</a> and <a href="#">Figure 19: "Switching time waveform"</a> )	-	13.5	-	ns
$t_r$	Voltage rise time		-	11.5	-	ns
$t_{d(off)}$	Turn-off delay time		-	72.5	-	ns
$t_f$	Current fall time		-	11.5	-	ns

Table 8: Source drain diode

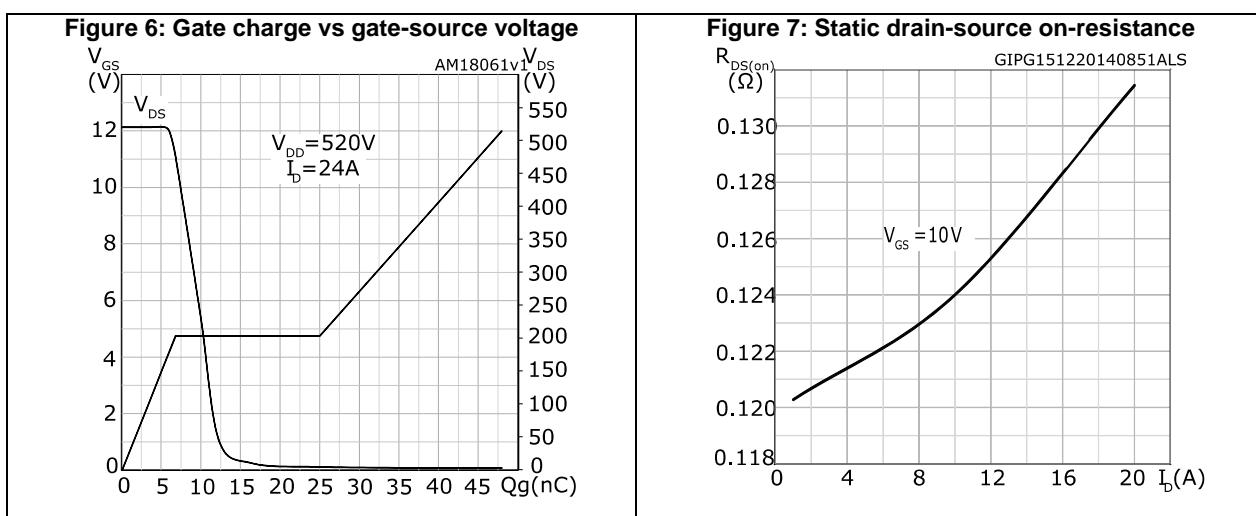
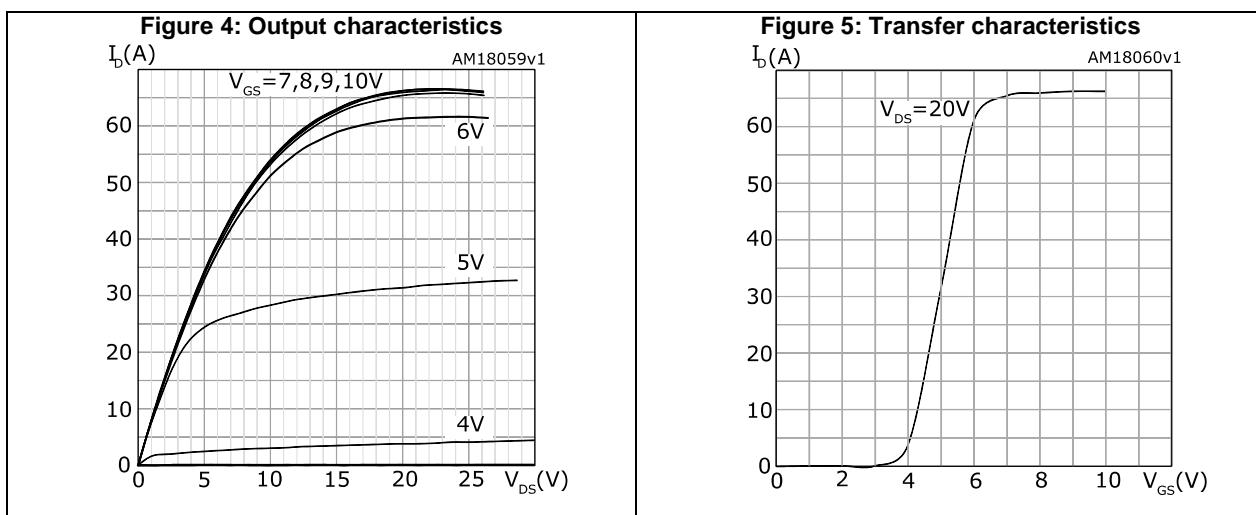
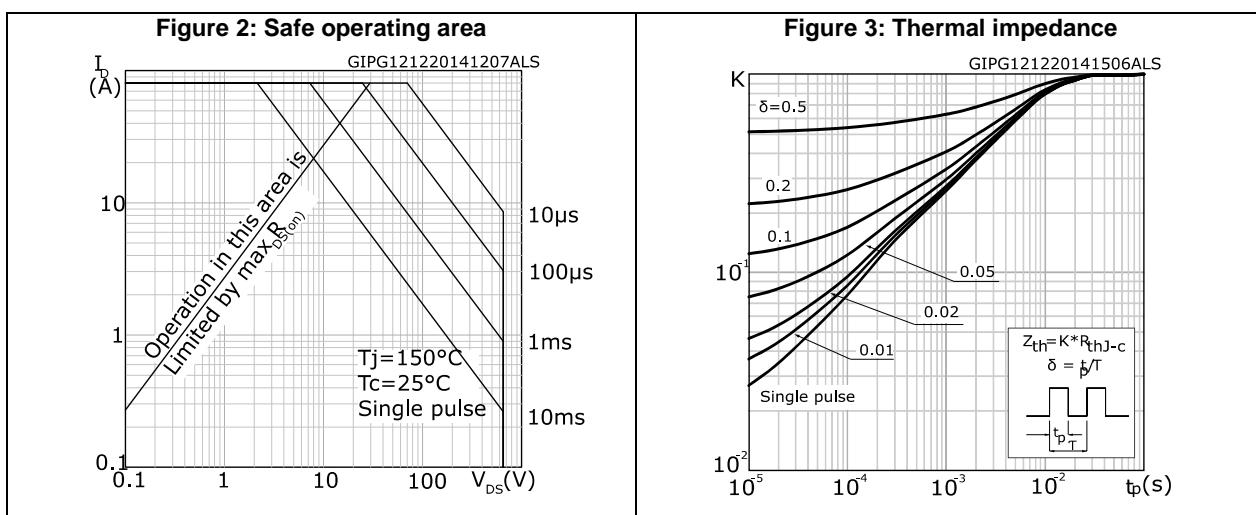
Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$I_{SD}$	Source-drain current		-		20	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)		-		80	A
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD} = 24 \text{ A}, V_{GS} = 0 \text{ V}$	-		1.6	V
$t_{rr}$	Reverse recovery time	$I_{SD} = 24 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}$ $V_{DD} = 60 \text{ V}$ (see <i>Figure 16: "Test circuit for inductive load switching and diode recovery times"</i> )	-	426		ns
$Q_{rr}$	Reverse recovery charge		-	7		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current		-	33.5		A
$t_{rr}$	Reverse recovery time	$I_{SD} = 24 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}$ $V_{DD} = 60 \text{ V}, T_j = 150 \text{ }^\circ\text{C}$ (see <i>Figure 16: "Test circuit for inductive load switching and diode recovery times"</i> )	-	544		ns
$Q_{rr}$	Reverse recovery charge		-	10		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current		-	36.5		A

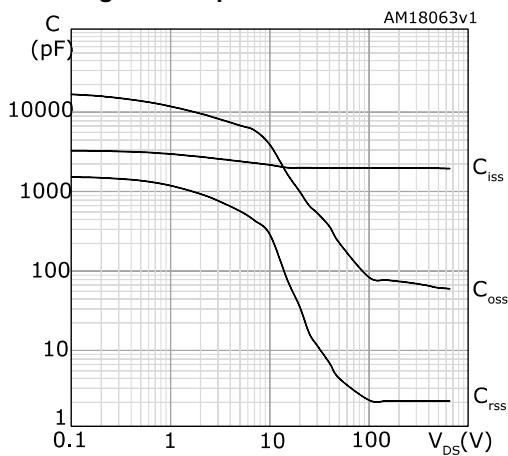
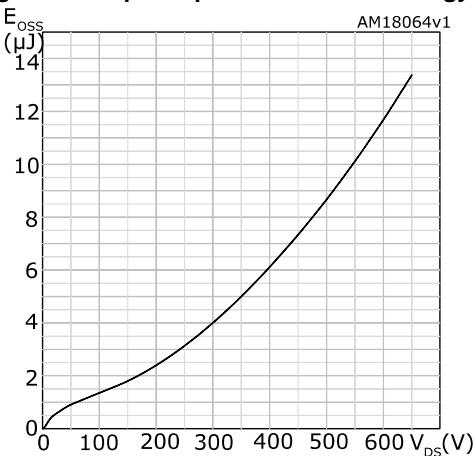
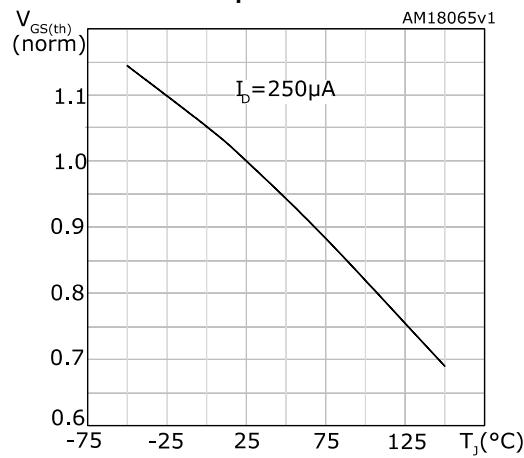
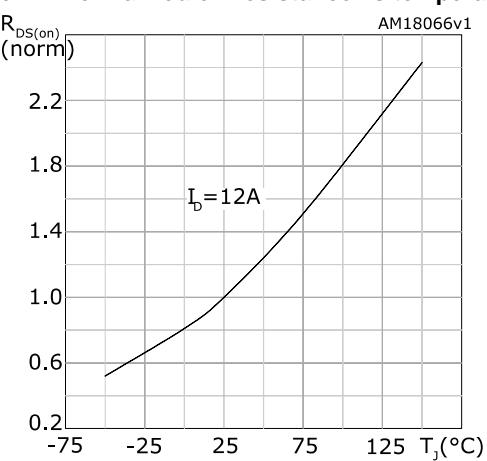
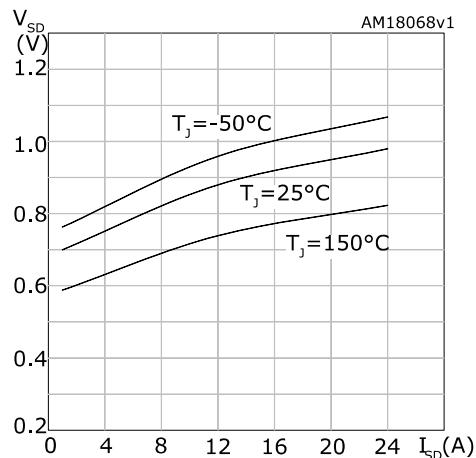
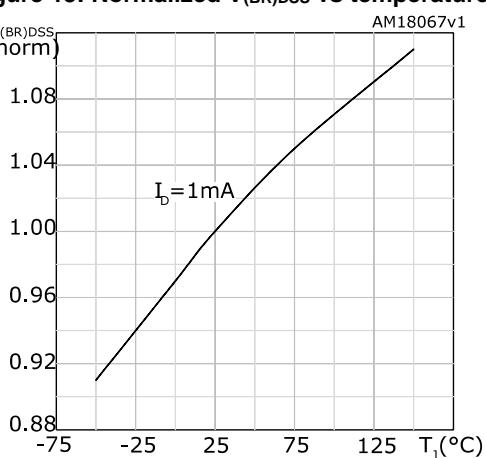
**Notes:**

(1)Pulse width limited by safe operating area.

(2)Pulsed: pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5%.

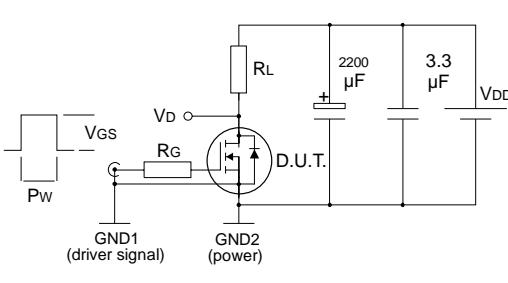
## 2.1 Electrical characteristics (curves)



**Figure 8: Capacitance variations****Figure 9: Output capacitance stored energy****Figure 10: Normalized gate threshold voltage vs temperature****Figure 11: Normalized on-resistance vs temperature****Figure 12: Source-drain diode forward characteristics****Figure 13: Normalized  $V_{(BR)DSS}$  vs temperature**

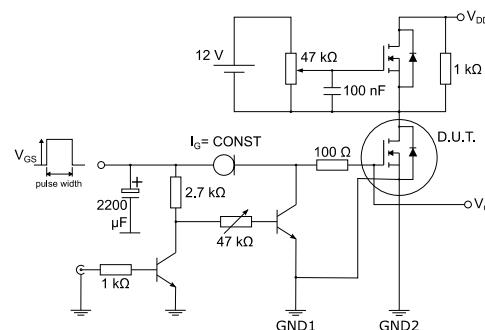
### 3 Test circuits

**Figure 14: Switching times test circuit for resistive load**



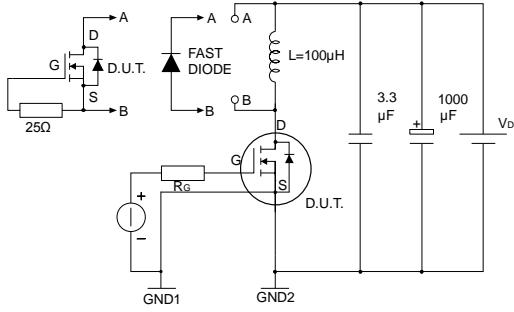
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**Figure 15: Gate charge test circuit**



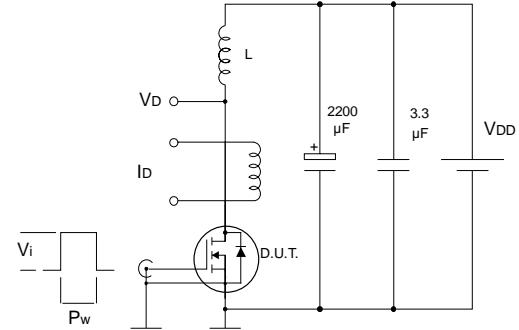
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**Figure 16: Test circuit for inductive load switching and diode recovery times**



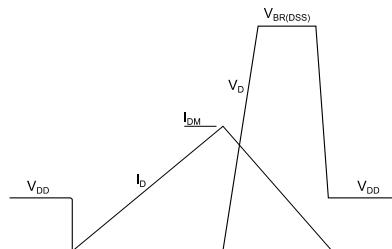
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**Figure 17: Unclamped inductive load test circuit**



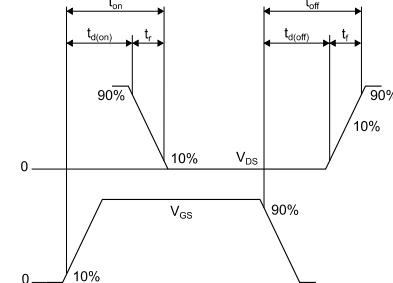
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**Figure 18: Unclamped inductive waveform**



AM01472v1

**Figure 19: Switching time waveform**



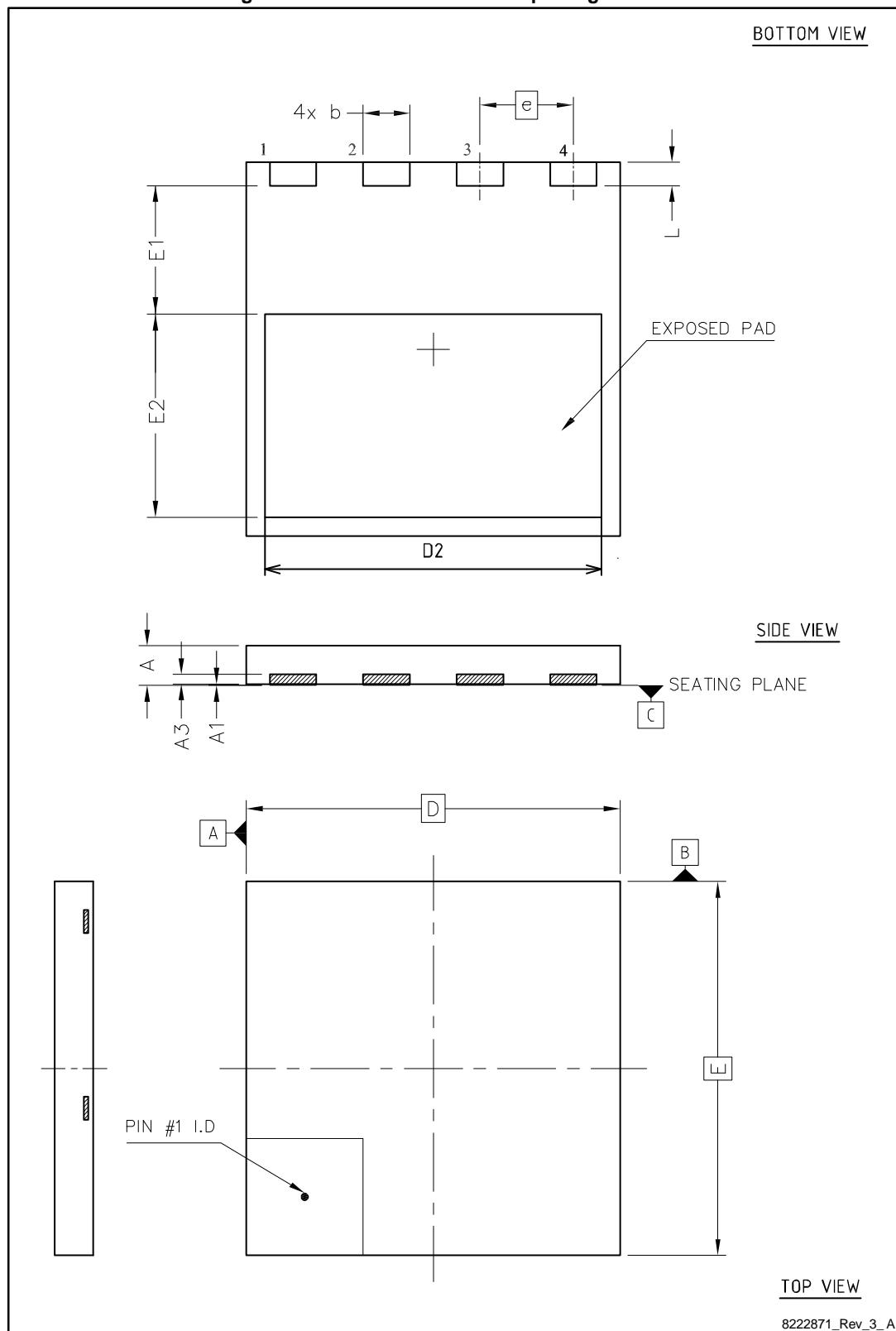
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## 4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com).  
ECOPACK® is an ST trademark.

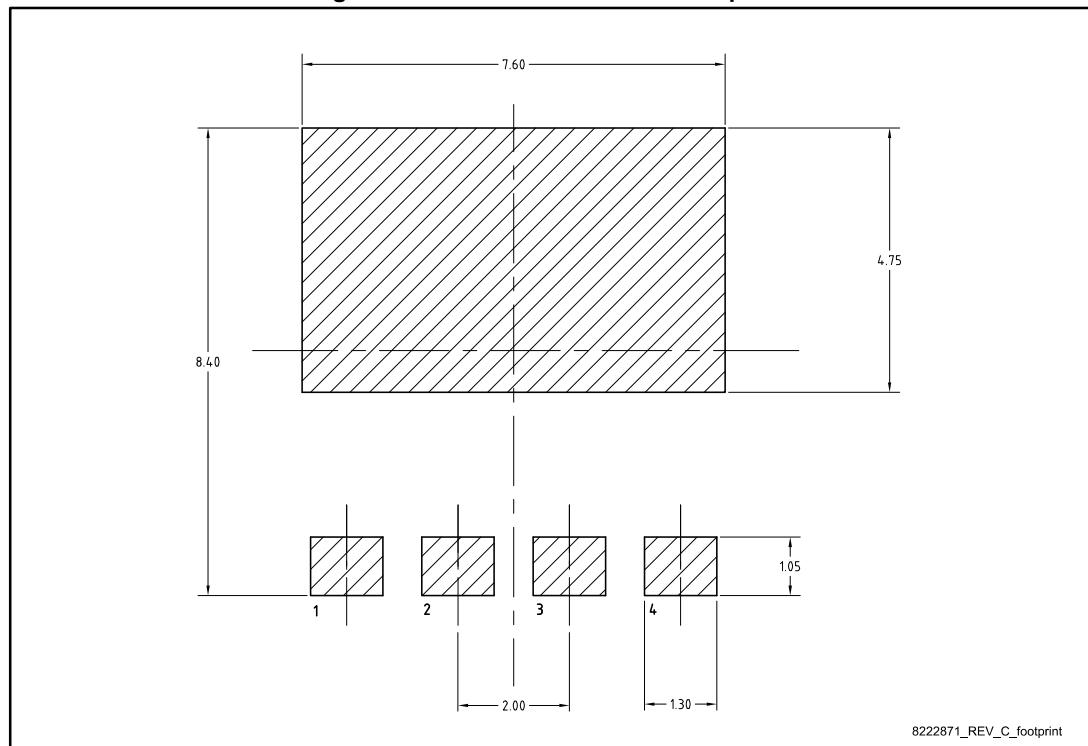
## 4.1 PowerFLAT™ 8x8 HV package information

Figure 20: PowerFLAT™ 8x8 HV package outline



**Table 9: PowerFLAT™ 8x8 HV mechanical data**

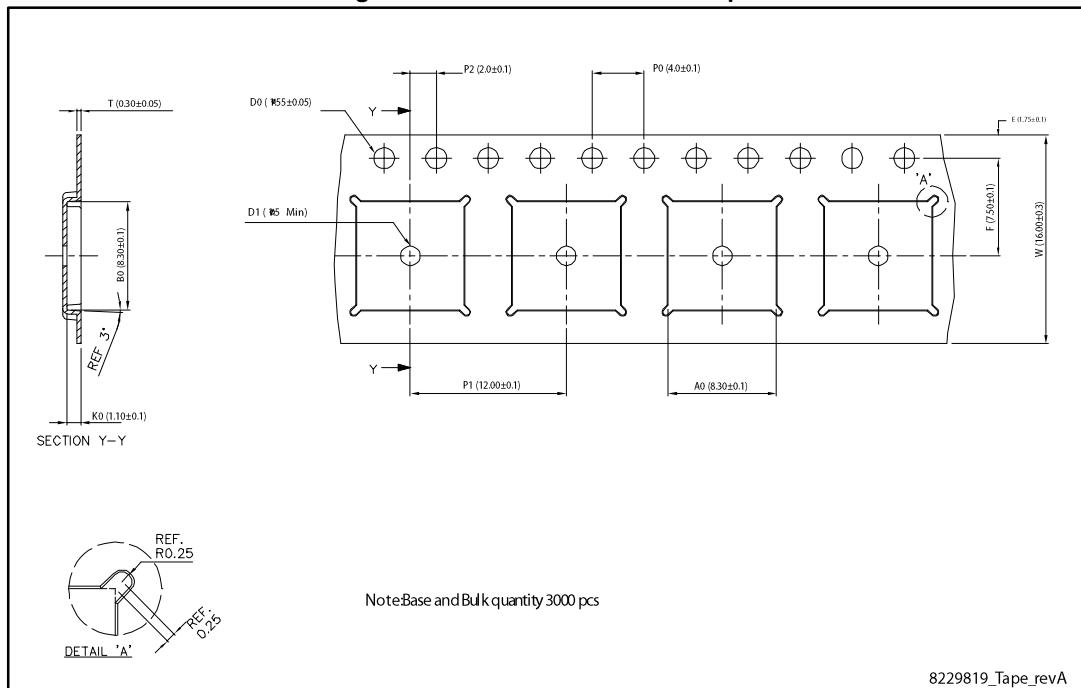
Dim.	mm		
	Min.	Typ.	Max.
A	0.75	0.85	0.95
A1	0.00		0.05
A3	0.10	0.20	0.30
b	0.90	1.00	1.10
D	7.90	8.00	8.10
E	7.90	8.00	8.10
D2	7.10	7.20	7.30
E1	2.65	2.75	2.85
E2	4.25	4.35	4.45
e		2.00	
L	0.40	0.50	0.60

**Figure 21: PowerFLAT™ 8x8 HV footprint**

All dimensions are in millimeters.

## 4.2 PowerFLAT™ 8x8 HV packing information

Figure 22: PowerFLAT™ 8x8 HV tape



All dimensions are in millimeters.

Figure 23: PowerFLAT™ 8x8 HV package orientation in carrier tape

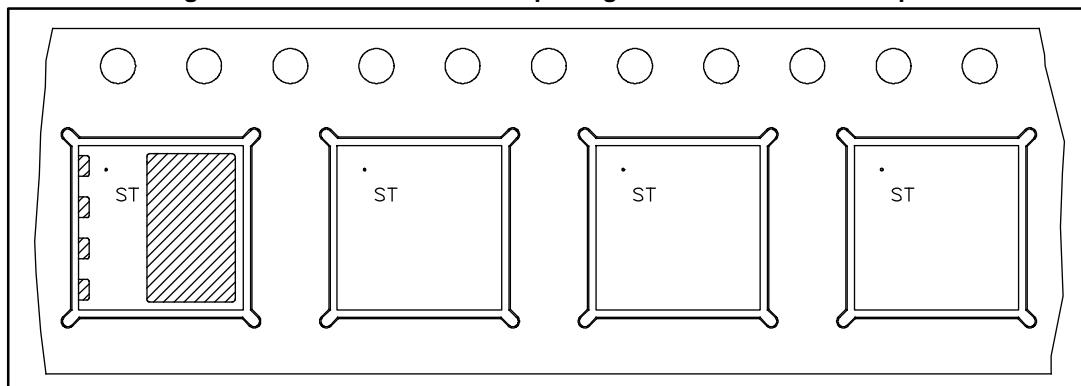
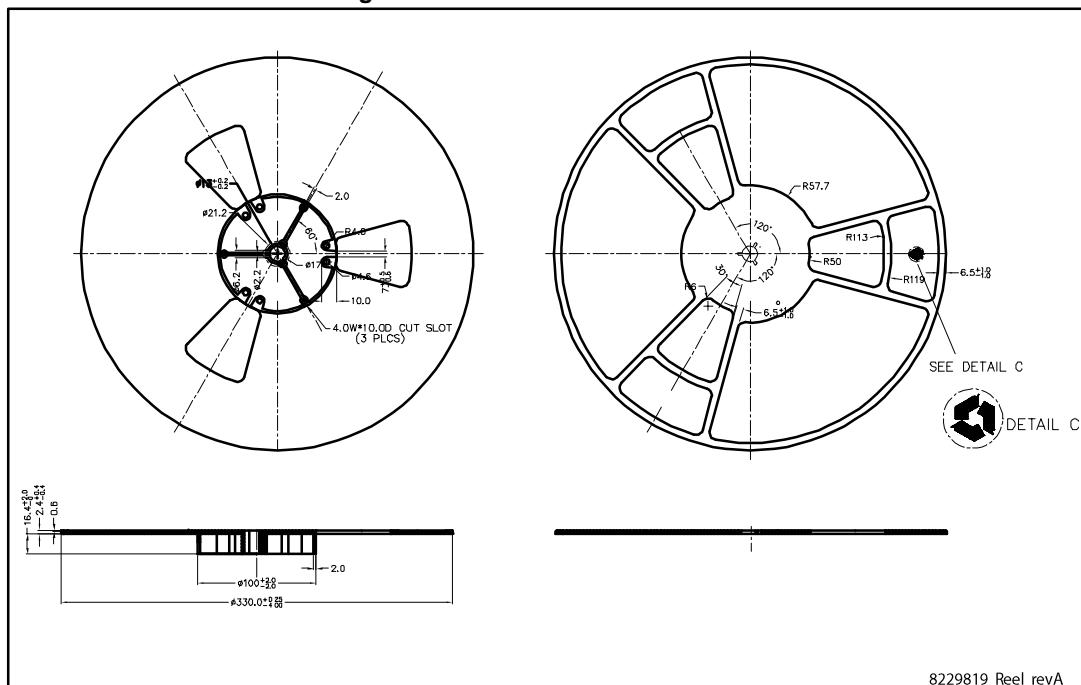


Figure 24: PowerFLAT™ 8x8 HV reel



All dimensions are in millimeters.

## 5 Revision history

Table 10: Document revision history

Date	Revision	Changes
26-Jun-2013	1	First release.
23-Jul-2014	2	Text edits throughout document. On cover page, updated title, features and description. Updated Table 2: Absolute maximum ratings. Updated Table 3: Thermal data. Added Table 4: Avalanche characteristics. Updated Table 5: On /off states. Updated Table 6: Dynamic. Updated Table 7: Switching times. Updated Table 8: Source drain diode.
13-Apr-2016	3	Updated cover image and <i>Figure 1: "Internal schematic diagram"</i> . Updated <i>Section 3: "Test circuits"</i> . Added footnote in <i>Table 5: "On /off states"</i> . Removed footnote in <i>Table 8: "Source drain diode"</i> . Updated <i>Section 4: "Package information"</i> . Minor text changes.

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